XA-9907 PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Haruki FUKAI et al.

Appln. No.:

Group Art Unit:

Filed: HEREWITH

For: SEMICONDUCTOR LASER, MANUFACTURING THE SAME AND

SEMICONDUCTOR LASER DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The documents on the attached List were cited in the specification, on page 2, and their relevance is indicated therein.

Respectfully submitted,

MWS:lat

Miles & Stockbridge P.C. 1751 Pinnacle Drive Suite 500 McLean, Virginia 22102-3833 (703) 903-9000

July 11, 2003

By:

Mitchell W. Shapiro

Reg. No. 31,568 [√]

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	Lin et al., "High-Temperature, Low Threshold Current, and Uniform Operation 1x12 Monolithic AlGaInAs/InP Strain-Compensated Multiple Quantum Well Laser Array in 1.5 µm," IEEE Transactions on Electron Devices, August 1999, Vol. 46, No. 8, pp. 1614-1618.							
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered Include copy of this form with next communication to Applicant.